


<b>Search Notes</b>  	<b>Application/Control No.</b>  10586991	<b>Applicant(s)/Patent Under Reexamination</b>  VORDE ET AL.
	<b>Examiner</b>  HENG M CHAN	<b>Art Unit</b>  1795

SEARCHED			
Class	Subclass	Date	Examiner
423	387	09/17/2008	/HMC/
149	delimited by text searching	09/24/2008	/HMC/
All searches updated		1/21/2009	/HMC/
564	59, 58	7/27/2009	HMC
ALL SEARCHES UPDATED		7/27/2009	HMC
UPDATED		3/2/2010	HMC
UPDATED		8/19/2010	HMC

SEARCH NOTES		
Search Notes	Date	Examiner
databases in EAST: US-PGPUB; USPAT; USOCR	9/17/2008	/HMC/
inventors searched in Palm	1/21/2009	/HMC/
All searches updated	1/21/2009	/HMC/
ALL SEARCHES UPDATED	7/27/2009	HMC
EAST databases: US-PGPUB; USPAT; USOCR, EPO, JPO, FPRS, DERWENT, IBM_TDB	7/27/2009	HMC
Consluted Jerry Lorengo about independent claims and arguments	7/27/2009	HMC
UPDATED	3/82010/	HMC
STN search	2/26/2010	HMC
Consulted Carlos Barcena	2/26/2010	HMC
STIC search	3/2/2010	HMC
Consulted Jennifer Michener	3/2/2010	HMC
UPDATED	8/19/2010	HMC
STN searches	8/19	HMC
Consulted Jennifer Michener about response to arguments	8/19	HMC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/H. M. C./  
Examiner.Art Unit 1793